**Product data sheet** 

# 1. General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

### 2. Features and benefits

- AEC Q101 compliant
- Low conduction losses due to low on-state resistance

# 3. Applications

Automotive and general purpose power switching

### 4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	-	100	V
I <sub>D</sub>	drain current	T <sub>mb</sub> = 25 °C		-	-	75	А
P <sub>tot</sub>	total power dissipation			-	-	300	W
Static characte	Static characteristics						,
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 25 ^{\circ}\text{C}$		-	12	15	mΩ
Avalanche ruggedness							
E <sub>DS(AL)S</sub>	non-repetitive drain- source avalanche energy	$I_D$ = 35 A; $V_{sup} \le$ 25 V; $R_{GS}$ = 50 Ω; $V_{GS}$ = 10 V; $T_{j(init)}$ = 25 °C; unclamped		-	-	120	mJ





# 5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate	mb	D I
2	D	drain	<del>                                     </del>	
3	S	source		G TITA
mb	D	mounting base; connected to drain		mbb076 S
			TO-220AB (SOT78A)	

# 6. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
BUK7515-100A	TO-220AB	plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB	SOT78A

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# 7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C	-	100	V
$V_{DGR}$	drain-gate voltage	$R_{GS}$ = 20 k $\Omega$	-	100	V
V <sub>GS</sub>	gate-source voltage		-20	20	V
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C	-	300	W
I <sub>D</sub>	drain current		-	75	Α
		T <sub>mb</sub> = 100 °C	-	60.8	Α
I <sub>DM</sub>	peak drain current	T <sub>mb</sub> = 25 °C; pulsed	-	240	Α
T <sub>stg</sub>	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
Source-drai	in diode		l		
Is	source current	T <sub>mb</sub> = 25 °C	-	75	Α
I <sub>SM</sub>	peak source current	pulsed; T <sub>mb</sub> = 25 °C	-	240	Α
Avalanche i	ruggedness	'	l l		
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$I_D$ = 35 A; $V_{sup} \le$ 25 V; $R_{GS}$ = 50 Ω; $V_{GS}$ = 10 V; $T_{j(init)}$ = 25 °C; unclamped	-	120	mJ

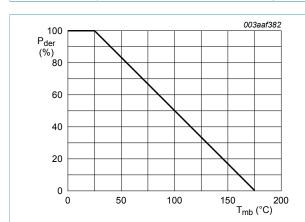
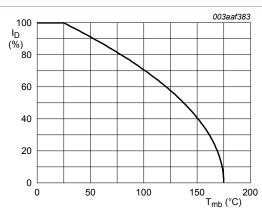


Fig. 1. Normalized total power dissipation as a function of mounting base temperature

$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$



V<sub>GS</sub> ≥ 10 V

Fig. 2. Normalized continuous drain current as a function of mounting base temperature

$$I_{der} = \frac{I_D}{I_{D(25^{\circ}C)}} \times 100\%$$

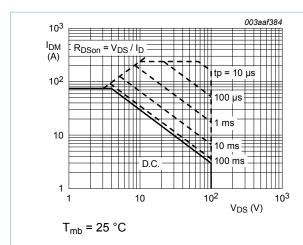


Fig. 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

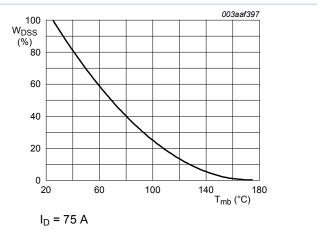


Fig. 4. Normalised drain-source non-repetitive avalanche energy as a function of mounting-base temperature

# 8. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base		-	-	0.5	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	in free air	-	60	-	K/W

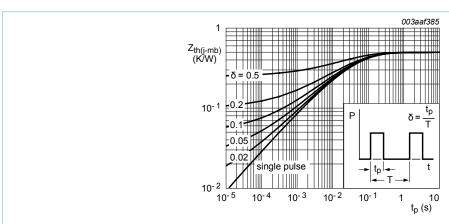


Fig. 5. Transient thermal impedance from junction to mounting base as a function of pulse duration

# 9. Characteristics

Table 6 Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static chara	octeristics		,			
V <sub>(BR)DSS</sub>	drain-source breakdown voltage	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	100	-	-	V
		I <sub>D</sub> = 0.25 mA; V <sub>GS</sub> = 0 V; T <sub>j</sub> = -55 °C	89	-	-	V
V <sub>GS(th)</sub>	gate-source threshold	I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = 25 °C	2	3	4	V
	voltage	I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = 175 °C	1	-	-	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ °C}$	-	-	4.4	V
I <sub>DSS</sub>	drain leakage current	V <sub>DS</sub> = 100 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 175 °C	-	-	500	μA
		V <sub>DS</sub> = 100 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 25 °C	-	0.05	10	μA
I <sub>GSS</sub>	gate leakage current	V <sub>GS</sub> = 20 V; V <sub>DS</sub> = 0 V; T <sub>j</sub> = 25 °C	-	2	100	nA
		V <sub>GS</sub> = -20 V; V <sub>DS</sub> = 0 V; T <sub>j</sub> = 25 °C	-	2	100	nA
R <sub>DSon</sub>	drain-source on-state	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 175 °C	-	-	40.5	mΩ
	resistance	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C	-	12	15	mΩ
Dynamic ch	aracteristics					
C <sub>iss</sub>	input capacitance	V <sub>GS</sub> = 0 V; V <sub>DS</sub> = 25 V; f = 1 MHz;	-	4500	6000	pF
C <sub>oss</sub>	output capacitance	T <sub>j</sub> = 25 °C	-	550	660	pF
C <sub>rss</sub>	reverse transfer capacitance		-	305	400	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS}$ = 30 V; $R_L$ = 1.2 $\Omega$ ; $V_{GS}$ = 10 V;	-	35	55	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 10 \Omega; T_j = 25 °C$	-	85	125	ns
t <sub>d(off)</sub>	turn-off delay time		-	150	225	ns
t <sub>f</sub>	fall time		-	70	100	ns
L <sub>D</sub>	internal drain inductance	from contact screw on tab to centre of die; $T_j = 25$ °C	-	3.5	-	nH
		from drain lead 6 mm from package to centre of die; T <sub>j</sub> = 25 °C	-	4.5	-	nΗ
L <sub>S</sub>	internal source inductance	from source lead 6 mm from package to source bond pad ; $T_j = 25 ^{\circ}\text{C}$	-	7.5	-	nΗ
Source-drai	n diode			1		
V <sub>SD</sub>	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	0.85	1.2	V
		I <sub>S</sub> = 75 A; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 25 °C	-	1.1	-	V
t <sub>rr</sub>	reverse recovery time	I <sub>S</sub> = 75 A; dI <sub>S</sub> /dt = -100 A/µs;	-	80	-	ns
Q <sub>r</sub>	recovered charge	$V_{GS} = -10 \text{ V}; V_{DS} = 30 \text{ V}; T_j = 25 \text{ °C}$	-	0.35	-	μC

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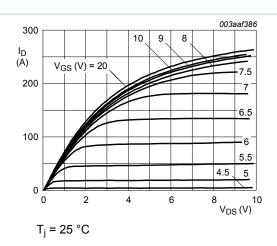


Fig. 6. Output characteristics: drain current as a function of drain-source voltage; typical values

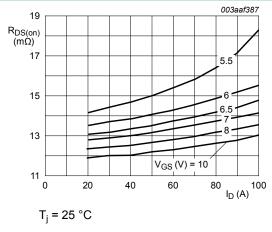


Fig. 7. Drain-source on-state resistance as a function of drain current; typical values

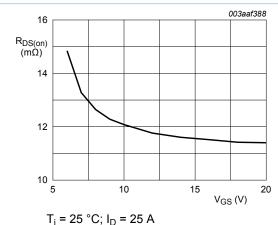


Fig. 8. Drain-source on-state resistance as a function of gate-sorce voltage; typical values

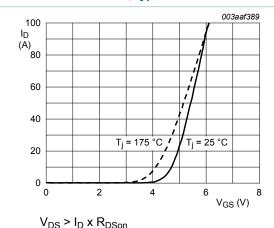


Fig. 9. Transfer characteristics: drain current as a function of gate-source voltage; typical values

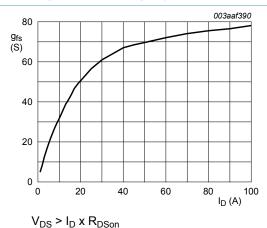


Fig. 10. Forward transconductance as a function of drain current; typical values

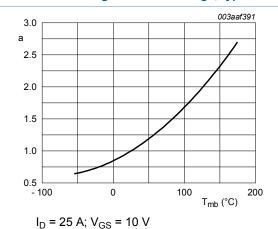


Fig. 11. Normalized drain-source on-state resistance factor as a function of junction temperature

$$a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$$

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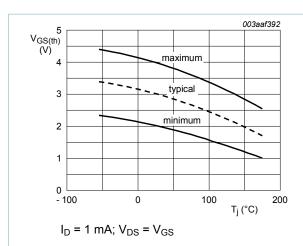


Fig. 12. Gate-source threshold voltage as a function of junction temperature

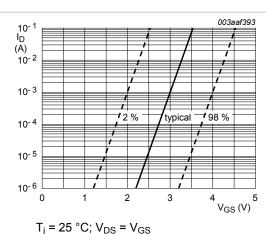
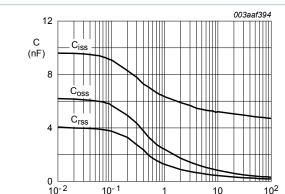


Fig. 13. Sub-threshold drain current as a function of

gate-source voltage



 $V_{GS} = 0 V; f = 1 MHz$ 

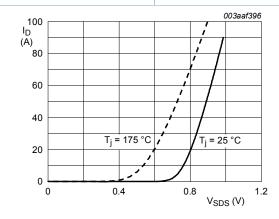
10-1

003aaf395 12  $V_{GS}$ 8 V<sub>DS</sub> = 80 V V<sub>DS</sub> = 14 V 0 40 80 120 Q<sub>G</sub> (nC)

 $T_i = 25 \,^{\circ}C; I_D = 25 \,^{\circ}A$ 

Fig. 14. Input, output and reverse transfer capacitances | Fig. 15. Gate-source voltage as a function of gate as a function of drain-source voltage; typical values





10<sup>2</sup>

V<sub>DS</sub> (V)

10

 $V_{GS} = 0 V$ 

Fig. 16. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

# 10. Package outline

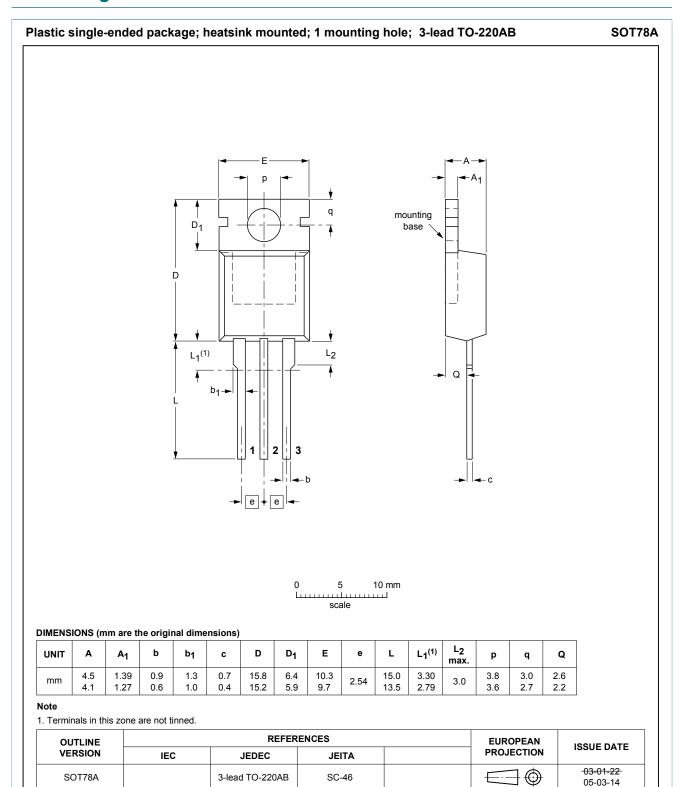


Fig. 17. Package outline TO-220AB (SOT78A)

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